

**Notice of References Cited**

Application/Control No.

10/566,686

Applicant(s)/Patent Under  
Reexamination  
LIU ET AL.

Examiner

JONATHAN C. LANGMAN

Art Unit

1784

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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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	U	Kanel et al., "Ballistic-Electron-Emission spectroscopy", Applied Physics A, Vol. 72, (2001), pgs S227-S232.
	V	Meyer et al., "Electron and hole Focusing in CoSi <sub>2</sub> /Si(111) Observed by ballistic Electron emission Microscopy", Physical Review Letters, Col. 85, 2000, pgs 1520-1523.
	W	Seto et al., "Si/SiGe resonant cavity photodiodes for optical storage applications", Applied Physics Letters, Vol. 72, 1998, pg 1550-1552.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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